

REMARKS

The claims are 3-7, and 30-35. Claims 3, 30, 32 and 34 have been amended. None of these amendments are narrowing and none are related to patentability. No new matter is introduced herein.

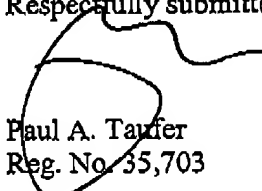
The Applicant would like to thank Examiner Chu for the courtesy of a telephone interview on July 19, 2004. Discussed in this Office Action were changes to the claims as set forth above, which would place the claims into allowable form.

Also discussed was that the Examiner requested an additional Form PTO-1449 for some clarifying language relating to references AR and AS noted in the prior Information Disclosure Statement filed with the last response on April 19, 2004. In reply, enclosed with this response is a new Form PTO-1449 which sets forth that document AR is a French language document and AS is related to AR in that AS contains an English translation of the AR reference.

The Examiner is kindly invited to contact the undersigned for any further discussion in relation to this response.

In view of all that is set forth above, Applicant respectfully requests allowance of the present application.

Respectfully submitted,



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PAT:ers
215-656-3385

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. 1575-00		SERIAL NO. 09/752,392	
LIST OF PRIOR ART CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT Tim Olson et al.			
				FILING DATE 12/29/2000		GROUP 2815	

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
	AR Coifman, R.R. and Y. Meyer, "Remarques sur l'analyse de Fourier à fenêtre", <i>Compte rendus de l'Academie des Sciences</i> , serie I: Mathematique, Vol. 312, pp. 259-261, 1991. (French)
	AS C.K. Chui, ed., <i>Wavelets: A Tutorial in Theory and Application</i> , Academic Press, "Local Sine and Cosine Bases of Coifman and Meyer and the construction of smooth wavelets," pp. 237-256, 1992. (English translation of document AR)

EXAMINER	DATE CONSIDERED
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MP2P 609; Draw line through citation if not in conformance and not considered.
 Include copy of this form with next communication to Applicant.